

**NANO QUALITY LEVELS IN THE CONSTRUCTION OF
DOUBLE SAMPLING PLAN OF THE TYPE DSP- (0,1)**

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ABSTRACT

Motorola (1980) introduced the concept of six sigma as a quality philosophy and a management strategy, which when adopted in a system of organization will reduce wastages and increase the profit to the management, in enhancing the satisfaction of the customer. If this concept of Six Sigma is adopted in an organization it can result in 3.4 or lower number of defects per million opportunities in the long run. In recent days many companies in developed and developing countries started working beyond Six Sigma level and thereby the performance level increases with number of defectives reduced to near zero level. In those situations a more stringent quality level than six sigma quality level, a concept of the 21st century is required to construct the sampling plan. In this paper a procedure for the construction of Double Sampling Plan of the type DSP-(0,1) indexed through producer's Nano quality level (PNQL) and consumer's Nano quality level (CNQL) is presented and suitable tables are also provided for the easy selection of the plans.

KEYWORDS

Nano Quality Level, Poisson distribution, Double Sampling Plan, Operating Characteristic curve.